- Member of the Texas Instruments Widebus ${ }^{\text {TM }}$ Family
- Advanced BiCMOS Technology
- Independent Asynchronous Inputs and Outputs
- Two Separate $512 \times 18$ FIFOs Buffering Data in Opposite Directions
- Programmable Almost-Full/Almost-Empty Flags
- Empty, Full, and Half-Full Flags
- Fast Access Times of 12 ns With a 50-pF Load and Simultaneous Switching Data Outputs
- Supports Clock Rates up to 67 MHz
- Package Options Include 80-Pin Quad Flat (PH) and 80-Pin Thin Quad Flat (PN) Packages



## (TOP VIEW)



## description

A FIFO memory is a storage device that allows data to be written into and read from its array at independent data rates. The SN74ABT7820 is arranged as two $512 \times 18$-bit FIFOs for high speed and fast access times. It processes data at rates up to 67 MHz with access times of 12 ns in a bit-parallel format.
The SN74ABT7820 consists of bus-transceiver circuits, two $512 \times 18$ FIFOs, and control circuitry arranged for multiplexed transmission of data directly from the data bus or from the internal FIFO memories. Enable inputs (GAB and GBA) control the transceiver functions. The SAB and SBA control inputs select whether real-time or stored data is transferred. The circuitry used for select control eliminates the typical decoding glitch that occurs in a multiplexer during the transition between stored and real-time data. Figure 1 illustrates the eight fundamental bus-management functions that can be performed with the SN74ABT7820.
The SN74ABT7820 is characterized for operation from $0^{\circ} \mathrm{C}$ to $70^{\circ} \mathrm{C}$.


Figure 1. Bus-Management Functions

SELECT-MODE CONTROL TABLE

| CONTROL |  | OPERATION |  |
| :---: | :---: | :---: | :---: |
| SBA | SAB | A BUS | B BUS |
| L | L | Real-time B-to-A bus | Real-time A-to-B bus |
| H | L | FIFO B-to-A bus | Real-time A-to-B bus |
| L | H | Real-time B-to-A bus | FIFO A-to-B bus |
| H | H | FIFO B-to-A bus | FIFO A-to-B bus |

OUTPUT-ENABLE CONTROL TABLE

| CONTROL |  | OPERATION |  |
| :---: | :---: | :---: | :---: |
| GBA | GAB | A BUS | B BUS |
| L | L | Isolation/input to A bus | Isolation/input to B bus |
| H | L | A bus enabled | Isolation/input to B bus |
| L | H | Isolation/input to A bus | B bus enabled |
| H | H | A bus enabled | B bus enabled |

Figure 1. Bus-Management Functions (Continued)
logic symbol $\dagger$

† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.
Pin numbers shown are for the PH package.
logic diagram (positive logic)


## Terminal Functions

| TERMINAL | I/O | DESCRIPTION |
| :---: | :---: | :---: |
| A0-A17 | I/O | Port-A data. The 18-bit bidirectional data port for side A. |
| AF/AEA | 0 | FIFO A almost-full/almost-empty flag. Depth-offset values can be programmed for AF/AEA or the default value of 128 can be used for both the almost-empty offset $(X)$ and the almost-full offset $(Y)$. AF/AEA is high when FIFO A contains $X$ or fewer words or ( $512-\mathrm{Y}$ ) or more words. AF/AEA is set high after FIFO A is reset. |
| AF/AEB | O | FIFO B almost-full/almost-empty flag. Depth-offset values can be programmed for AF/AEB or the default value of 128 can be used for both the almost-empty offset $(X)$ and the almost-full offset (Y). AF/AEB is high when FIFO B contains $X$ or fewer words or ( $512-\mathrm{Y}$ ) or more words. AF/AEB is set high after FIFO B is reset. |
| B0-B17 | I/O | Port-B data. The 18-bit bidirectional data port for side B. |
| $\overline{\text { EMPTYA }}$ | O | FIFO A empty flag. EMPTYA is low when FIFO A is empty and high when FIFO A is not empty. EMPTYA is set low after FIFO $A$ is reset. |
| $\overline{\text { EMPTYB }}$ | O | FIFO B empty flag. $\overline{\text { EMPTYB }}$ is low when FIFO B is empty and high when FIFO B is not empty. $\overline{\text { EMPTYB }}$ is set low after FIFO $B$ is reset. |
| $\overline{\text { FULLA }}$ | O | FIFO A full flag. $\overline{\text { FULLA }}$ is low when FIFO $A$ is full and high when FIFO $A$ is not full. $\overline{\text { FULLA }}$ is set high after FIFO $A$ is reset. |
| $\overline{\text { FULLB }}$ | O | FIFO B full flag. $\overline{\text { FULLB }}$ is low when FIFO $B$ is full and high when FIFO $B$ is not full. $\overline{\text { FULLB }}$ is set high after FIFO $B$ is reset. |
| GAB | I | Port-B output enable. B0-B17 outputs are active when GAB is high and in the high-impedance state when GAB is low. |
| GBA | I | Port-A output enable. A0-A17 outputs are active when GBA is high and in the high-impedance state when GBA is low. |
| HFA | O | FIFO A half-full flag. HFA is high when FIFO A contains 256 or more words and is low when FIFO A contains 255 or fewer words. HFA is set low after FIFO A is reset. |
| HFB | O | FIFO B half-full flag. HFB is high when FIFO B contains 256 or more words and is low when FIFO B contains 255 or fewer words. HFB is set low after FIFO B is reset. |
| LDCKA | 1 | FIFO A load clock. Data is written into FIFO A on a low-to-high transition of LDCKA when FULLA is high. The first word written into an empty FIFO A is sent directly to the FIFO A data outputs. |
| LDCKB | 1 | FIFO B load clock. Data is written into FIFO B on a low-to-high transition of LDCKB when $\overline{\text { FULLB }}$ is high. The first word written into an empty FIFO B is sent directly to the FIFO B data outputs. |
| $\overline{\text { PENA }}$ | I | FIFO A program enable. After reset and before a word is written into FIFO A, the binary value on A0-A7 is latched as an AF/AEA offset value when $\overline{\text { PENA }}$ is low and LDCKA is high. |
| $\overline{\text { PENB }}$ | \| | FIFO B program enable. After reset and before a word is written into FIFO B, the binary value on B0-B7 is latched as an AF/AEB offset value when $\overline{\text { PENB }}$ is low and LDCKB is high. |
| $\overline{\text { RSTA }}$ | I | FIFO A reset. A low level on $\overline{\text { RSTA }}$ resets FIFO A forcing EMPTYA low, HFA low, $\overline{\text { FULLA }}$ high, and AF/AEA high. |
| $\overline{\text { RSTB }}$ | I | FIFO B reset. A low level on $\overline{\text { RSTB }}$ resets FIFO B forcing $\overline{\overline{E M P T Y B}}$ low, HFB low, $\overline{\text { FULLB }}$ high, and AF/AEB high. |
| SAB | I | Port- B read select. SAB selects the source of $\mathrm{B} 0-\mathrm{B} 17$ read data. A low level selects real-time data from $\mathrm{A} 0-\mathrm{A} 17$. A high level selects the FIFO A output. |
| SBA | 1 | Port-A read select. SBA selects the source of A0-A17 read data. A low level selects real-time data from B0 - B17. A high level selects the FIFO B output. |
| UNCKA | I | FIFO A unload clock. Data is read from FIFO A on a low-to-high transition of UNCKA when EMPTYA is high. |
| UNCKB | I | FIFO B unload clock. Data is read from FIFO B on a low-to-high transition of UNCKB when EMPTYB is high. |



Figure 2. Timing Diagram for FIFO $A^{\dagger}$

## offset values for AF/AE

The AF/AE flag of each FIFO has two programmable limits: the almost-empty offset value $(X)$ and the almost-full offset value ( Y ). The offsets of a flag can be programmed from the input of its FIFO after it is reset and before any data is written to its memory. An AF/AE flag is high when its FIFO contains X or fewer words or ( $512-\mathrm{Y}$ ) or more words.

To program the offset values for AF/AEA, program enable ( $\overline{\mathrm{PENA}}$ ) can be brought low after FIFO A is reset and only when LDCKA is low. On the following low-to-high transition of LDCKA, the binary value on A0-A7 is stored as the almost-empty offset value $(\mathrm{X})$ and the almost-full offset value ( Y ). Holding PENA low for another low-to-high transition of LDCKA reprograms Y to the binary value on $\mathrm{A} 0-\mathrm{A} 7$ at the time of the second LDCKA low-to-high transition.
$\overline{\text { PENA }}$ can be brought back high only when LDCKA is low during the first two LDCKA cycles. $\overline{\text { PENA }}$ can be brought high at any time after the second LDCKA pulse returns low. A maximum value of 255 can be programmed for either $X$ or $Y$ (see Figure 3). To use the default values of $X=Y=128$ for AF/AEA, $\overline{P E N A}$ must be tied high. No data is stored in the FIFO when its AF/AE offsets are programmed. The AF/AEB flag is programmed in the same manner. $\overline{\text { PENB }}$ enables LDCKB to program the AF/AEB offset values taken from B0-B7.


Figure 3. Programming $X$ and $Y$ Separately for AF/AEA

## absolute maximum ratings over operating free-air temperature (unless otherwise noted) $\dagger$

$$
\begin{aligned}
& \text { Input voltage range, } \mathrm{V}_{\mathrm{I}} \text { (see Note 1) . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . }-0.5 \mathrm{~V} \text { to } \mathrm{V}_{\mathrm{CC}}+0.5 \mathrm{~V} \\
& \text { Voltage range applied to any output in the high state or power-off state, } \mathrm{V}_{\mathrm{O}} \ldots \ldots . \ldots . \mathrm{I}_{\mathrm{O}} \ldots-0.5 \mathrm{~V} \text { to } 5.5 \mathrm{~V} \\
& \text { Current into any output in the low state, } \mathrm{I}_{\mathrm{O}} \text {. . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . } 48 \mathrm{~mA} \\
& \text { Input clamp current, } \mathrm{I}_{\mathrm{IK}}\left(\mathrm{~V}_{\mathrm{I}}<0\right) \text {. . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . } 18 \mathrm{~mA} \\
& \text { Output clamp current, } \mathrm{I}_{\mathrm{OK}}\left(\mathrm{~V}_{\mathrm{O}}<0\right) \text {. . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . } 50 \mathrm{~mA} \\
& \text { Package thermal impedance, } \theta_{J A} \text { (see Note 2): PH package . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . 76² } \mathrm{C} / \mathrm{W}
\end{aligned}
$$

$$
\begin{aligned}
& \text { Storage temperature range, } \mathrm{T}_{\text {stg }} \text {. . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . . }-65^{\circ} \mathrm{C} \text { to } 150^{\circ} \mathrm{C} \\
& \dagger \text { Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and } \\
& \text { functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not } \\
& \text { implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. } \\
& \text { NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed. } \\
& \text { 2. The package thermal impedance is calculated in accordance with JESD } 51 .
\end{aligned}
$$

recommended operating conditions

|  |  | MIN | NOM |
| :--- | :--- | ---: | ---: |
| $\mathrm{V}_{\mathrm{CC}}$ | Supply voltage | MAX | UNIT |
| $\mathrm{V}_{\mathrm{IH}}$ | High-level input voltage | 4.5 | 5 |
| $\mathrm{~V}_{\mathrm{IL}}$ | Low-level input voltage | 5.5 | V |
| $\mathrm{~V}_{\mathrm{I}}$ | Input voltage |  |  |
| $\mathrm{IOH}_{\mathrm{OH}}$ | High-level output current | 0 | 0.8 |
| $\mathrm{IOL}_{\mathrm{OL}}$ | Low-level output current | V |  |
| $\Delta \mathrm{l} / \Delta \mathrm{V}$ | Input transition rise or fall rate | $\mathrm{V}_{\mathrm{CC}}$ | V |
| $\mathrm{T}_{\mathrm{A}}$ | Operating free-air temperature | -12 | mA |

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

| PARAMETER |  | TEST CONDITIONS |  |  |  | MIN | TYPt | MAX | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\mathrm{IK}}$ |  | $\mathrm{V}_{\mathrm{CC}}=4.5 \mathrm{~V}$, | $\boldsymbol{I}=-18 \mathrm{~mA}$ |  |  | -1.2 |  |  | V |
| $\mathrm{V}_{\mathrm{OH}}$ |  | $\mathrm{V}_{\mathrm{CC}}=4.5 \mathrm{~V}$, | $\mathrm{IOH}=-3 \mathrm{~mA}$ |  |  | 2.5 |  |  | V |
|  |  | $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}$, | $\mathrm{IOH}=-3 \mathrm{~mA}$ |  |  | 3 |  |  |  |
|  |  | $\mathrm{V}_{\mathrm{CC}}=4.5 \mathrm{~V}$, | $\mathrm{I}^{\mathrm{OH}}=-$ |  |  | 2 |  |  |  |
| V OL |  | $\mathrm{V}_{\mathrm{CC}}=4.5 \mathrm{~V}$, | $\mathrm{IOL}=24 \mathrm{~mA}$ |  |  |  |  | 0.55 | V |
| I |  | $\mathrm{V}_{\mathrm{CC}}=5.5 \mathrm{~V}$, | $\mathrm{V}_{1}=\mathrm{V}_{\mathrm{CC}}$ or GND |  |  |  |  | $\pm 5$ | $\mu \mathrm{A}$ |
| $\mathrm{IOZH}^{\ddagger}$ |  | $\mathrm{V}_{\mathrm{CC}}=5.5 \mathrm{~V}$, | $\mathrm{V}_{\mathrm{O}}=2.7 \mathrm{~V}$ |  |  |  |  | 50 | $\mu \mathrm{A}$ |
| lozl ${ }^{\ddagger}$ |  | $\mathrm{V}_{\mathrm{CC}}=5.5 \mathrm{~V}$, | $\mathrm{V}_{\mathrm{O}}=0.5 \mathrm{~V}$ |  |  |  |  | -50 | $\mu \mathrm{A}$ |
| $10^{\text {§ }}$ |  | $\mathrm{V}_{\mathrm{CC}}=5.5 \mathrm{~V}$, | $\mathrm{V}_{\mathrm{O}}=2.5 \mathrm{~V}$ |  |  | -40 | -100 | -180 | mA |
| ICC |  | $\mathrm{V}_{\mathrm{CC}}=5.5 \mathrm{~V}$, | $\mathrm{l}=0$, | $\mathrm{V}_{\mathrm{I}}=\mathrm{V}_{\mathrm{CC}}$ or GND | Outputs high |  |  | 15 | mA |
|  |  | Outputs low |  |  |  |  | 95 |  |
|  |  | Outputs disabled |  |  |  |  | 15 |  |
| $\mathrm{C}_{\mathrm{i}}$ | Control inputs |  | $\mathrm{V}_{\mathrm{I}}=2.5 \mathrm{~V}$ or 0.5 V |  |  |  | 6 |  |  | pF |
| $\mathrm{C}_{0}$ | Flags |  | $\mathrm{V}_{\mathrm{O}}=2.5 \mathrm{~V}$ or 0.5 V |  |  |  |  | 4 |  | pF |
| $\mathrm{C}_{\mathrm{i}}$ | A or B ports | $\mathrm{V}_{\mathrm{O}}=2.5 \mathrm{~V}$ or 0.5 V |  |  |  |  | 8 |  | pF |

$\dagger$ All typical values are at $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$.
$\ddagger$ The parameters $\mathrm{I}_{\mathrm{OZH}}$ and $\mathrm{I}_{\mathrm{OZL}}$ include the input leakage current.
§ Not more than one output should be tested at a time, and the duration of the test should not exceed one second.
timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 2 through 4)

|  |  |  | 'ABT7820-15 |  | 'ABT7820-20 |  | 'ABT7820-25 |  | 'ABT7820-30 |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | MIN | MAX | MIN | MAX | MIN | MAX | MIN | MAX |  |
| ${ }_{\text {f clock }}$ | Clock frequency |  |  | 67 |  | 50 |  | 40 |  | 33 | MHz |
| ${ }^{\text {tw }}$ | Pulse duration | LDCKA, LDCKB high | 4 |  | 6 |  | 9 |  | 11 |  | ns |
|  |  | LDCKA, LDCKB low | 4 |  | 6 |  | 9 |  | 11 |  |  |
|  |  | UNCKA, UNCKB high | 4 |  | 6 |  | 9 |  | 11 |  |  |
|  |  | UNCKA, UNCKB low | 4 |  | 6 |  | 9 |  | 11 |  |  |
|  |  | $\overline{\mathrm{RSTA}}, \overline{\mathrm{RSTB}}$ low | 6 |  | 8 |  | 10 |  | 12 |  |  |
| $\mathrm{t}_{\text {su }}$ | Setup time | A0-A17 before LDCKA $\uparrow$ and B0-B17 before LDCKB $\uparrow$ | 3 |  | 4 |  | 4 |  | 4 |  | ns |
|  |  | $\overline{\text { PENA }}$ before LDCKA $\uparrow$ and $\overline{\text { PENB }}$ before LDCKB $\uparrow$ | 5 |  | 5 |  | 5 |  | 5 |  |  |
|  |  | LDCKA inactive before $\overline{\text { RSTA }}$ high and LDCKB inactive before $\overline{\text { RSTB }}$ high | 3 |  | 3 |  | 4 |  | 4 |  |  |
| th | Hold time | A0-A17 after LDCKA $\uparrow$ and B0-B17 after LDCKB $\uparrow$ | 0 |  | 0 |  | 0 |  | 0 |  | ns |
|  |  | $\overline{\text { PENA }}$ after LDCKA low and PENB after LDCKB low | 2 |  | 2 |  | 2 |  | 2 |  |  |
|  |  | LDCKA inactive after $\overline{\text { RSTA }}$ high and LDCKB inactive after $\overline{\text { RSTB }}$ high | 3 |  | 3 |  | 4 |  | 4 |  |  |

switching characteristics over recommended ranges of supply voltage and operating free－air temperature， $\mathrm{C}_{\mathrm{L}}=50 \mathrm{pF}$（unless otherwise noted）（see Figure 5）

| PARAMETER | FROM （INPUT） | TO （OUTPUT） | ＇ACT7820－15 |  |  | ＇ACT7820－20 |  | ＇ACT7820－25 |  | ＇ACT7820－30 |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | MIN | TYP† | MAX | MIN | MAX | MIN | MAX | MIN | MAX |  |
| ${ }_{\text {fax }}$ | LDCK，UNCK |  | 67 |  |  | 50 |  | 40 |  | 33.3 |  | MHz |
| ${ }^{\text {tpd }}$ | LDCKA $\uparrow$ ， LDCKB $\uparrow$ | B／A | 4 |  | 14 | 4 | 15 | 4 | 18 | 4 | 20 | ns |
|  | UNCKA $\uparrow$ ， UNCKB $\uparrow$ |  | 4 | 9 | 12 | 4 | 13.5 | 4 | 15 | 4 | 17 |  |
| $t_{p d}{ }^{\ddagger}$ | UNCKAT， UNCKB $\uparrow$ | B／A |  | 8 |  |  |  |  |  |  |  | ns |
| tPLH | LDCKA个， LDCKB $\uparrow$ | $\frac{\overline{\text { EMPTYA, }}}{\frac{\text { EMPTYB }}{}}$ | 4 |  | 14 | 4 | 15 | 4 | 17 | 4 | 19 | ns |
| tPHL | UNCKA个， UNCKB $\uparrow$ |  | 4 |  | 13 | 4 | 14 | 4 | 16 | 4 | 18 |  |
| tPHL | $\begin{aligned} & \hline \overline{\text { RSTA }} \text { low, } \\ & \text { RSTB low } \end{aligned}$ | $\begin{aligned} & \hline \overline{\mathrm{EMPTYA}}, \\ & \hline \text { EMPTYB } \end{aligned}$ | 6 |  | 16 | 6 | 16 | 6 | 18 | 6 | 20 | ns |
| tPHL | LDCKA $\uparrow$ ， LDCKB $\uparrow$ | $\overline{\overline{\text { FULLA }},} \overline{\overline{\text { FULLB }}}$ | 6 |  | 13 | 6 | 14 | 6 | 16 | 6 | 18 | ns |
| tPLH | UNCKA个， UNCKB $\uparrow$ | $\frac{\overline{\text { FULLA }}}{\overline{\text { FULLB }}}$ | 6 |  | 15 | 6 | 15 | 6 | 17 | 6 | 19 | ns |
|  | $\begin{aligned} & \hline \overline{\mathrm{RSTA}} \text { low, } \end{aligned}$ |  | 8 |  | 20 | 8 | 20 | 8 | 22 | 8 | 22 |  |
| $t_{\text {pd }}$ | LDCKA LDCKB $\uparrow$ | AF／AEA， AF／AEB | 8 |  | 16 | 8 | 17 | 8 | 18 | 8 | 20 | ns |
|  | UNCKA个， UNCKB $\uparrow$ |  | 8 |  | 16 | 8 | 17 | 8 | 18 | 8 | 20 |  |
| tPLH | $\begin{aligned} & \overline{\overline{\text { RSTA }} \text { low, }} \\ & \text { RSTB low } \end{aligned}$ | AF／AEA， AF／AEB | 2 |  | 12 | 2 | 14 | 2 | 16 | 2 | 18 | ns |
| tPLH | LDCKA $\uparrow$ ， LDCKB $\uparrow$ | HFA，HFB | 8 |  | 15 | 8 | 15 | 8 | 17 | 8 | 19 | ns |
|  | UNCKA，UNCKB | HFA，HFB | 8 |  | 15 | 8 | 15 | 8 | 17 | 8 | 19 | ns |
| tPHL | $\begin{aligned} & \overline{\overline{\mathrm{RSTA}}} \text { low, } \\ & \overline{\mathrm{RSTB}} \text { low } \end{aligned}$ |  | 2 |  | 12 | 2 | 14 | 2 | 16 | 2 | 18 |  |
| ${ }^{\text {tpd }}$ | SAB／SBA§ | B／A | 2 |  | 10 | 2 | 11 | 2 | 12 | 2 | 14 | ns |
|  | A／B |  | 2 |  | 9 | 2 | 10 | 2 | 11 | 2 | 13 |  |
| ten | GBA／GAB | A／B | 2 |  | 6.5 | 2 | 8 | 2 | 10 | 2 | 12 | ns |
| $\mathrm{t}_{\text {dis }}$ | GBA／GAB | A／B | 2 |  | 11 | 2 | 12 | 2 | 13 | 2 | 14 | ns |

$\dagger$ All typical values are at $5 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ ．
$\ddagger$ This parameter is measured with a $30-\mathrm{pF}$ load（see Figure 5）．
§ These parameters are measured with the internal output state of the storage register opposite that of the bus input．

PARAMETER MEASUREMENT INFORMATION


VOLTAGE WAVEFORMS PROPAGATION DELAY TIMES

| PARAMETER |  | S1 |
| :---: | :---: | :---: |
| $t_{\text {en }}$ | tPZH | Open |
|  | tPZL | Closed |
| ${ }^{\text {dis }}$ | ${ }^{\text {tPHZ }}$ | Open |
|  | tplZ | Closed |
| $t_{\text {pd }}$ | ${ }^{\text {tPLH }}$ | Open |
|  | tPHL | Open |



VOLTAGE WAVEFORMS PULSE DURATION


VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

NOTE A: $C_{L}$ includes probe and jig capacitance.
Figure 4. Load Circuit and Voltage Waveforms

## TYPICAL CHARACTERISTICS



Figure 5


Figure 6
www.ti.com

## PACKAGING INFORMATION

| Orderable Device | Status ${ }^{(1)}$ | Package <br> Type | Package <br> Drawing | Pins Package <br> Qty | Eco Plan ${ }^{(2)}$ | Lead/Ball Finish | MSL Peak Temp ${ }^{(3)}$ |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| 1O7820-15PNG4 | ACTIVE | LQFP | PN | 80 | 119 |  <br> no Sb/Br) | CU NIPDAU | Level-3-260C-168 HR |
| 1O7820-20PNG4 | ACTIVE | LQFP | PN | 80 | 119 |  <br> no Sb/Br) | CU NIPDAU | Level-3-260C-168 HR |
| SN74ABT7820-15PH | ACTIVE | QFP | PH | 80 | 66 | TBD | A42 | Level-3-220C-168 HR |
| SN74ABT7820-15PN | ACTIVE | LQFP | PN | 80 | 119 |  <br> no Sb/Br) | CU NIPDAU | Level-3-260C-168 HR |
| SN74ABT7820-20PH | ACTIVE | QFP | PH | 80 | 66 | TBD | A42 | Level-3-220C-168 HR |
| SN74ABT7820-20PN | ACTIVE | LQFP | PN | 80 | 119 |  <br> no Sb/Br) | CU NIPDAU | Level-3-260C-168 HR |
| SN74ABT7820-25PH | ACTIVE | QFP | PH | 80 | 66 | TBD | A42 | Level-3-220C-168 HR |
| SN74ABT7820-25PN | ACTIVE | LQFP | PN | 80 | 119 |  <br> no Sb/Br) | CU NIPDAU | Level-3-260C-168 HR |
| SN74ABT7820-30PH | ACTIVE | QFP | PH | 80 | 66 | TBD | A42 | Level-3-220C-168 HR |
| SN74ABT7820-30PN | ACTIVE | LQFP | PN | 80 | 119 |  <br> no Sb/Br) | CU NIPDAU | Level-3-260C-168 HR |

${ }^{(1)}$ The marketing status values are defined as follows:
ACTIVE: Product device recommended for new designs.
LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.
NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.
PREVIEW: Device has been announced but is not in production. Samples may or may not be available.
OBSOLETE: TI has discontinued the production of the device.
${ }^{(2)}$ Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS \& no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.
TBD: The Pb-Free/Green conversion plan has not been defined.
Pb -Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed $0.1 \%$ by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb -Free products are suitable for use in specified lead-free processes.
Pb -Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.
Green (RoHS \& no $\mathbf{S b} / \mathrm{Br}$ ): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine ( Br ) and Antimony ( Sb ) based flame retardants ( Br or Sb do not exceed $0.1 \%$ by weight in homogeneous material)
${ }^{(3)}$ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

Important Information and Disclaimer:The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

## OTHER QUALIFIED VERSIONS OF SN74ABT7820 :

- Military: SN54ABT7820

NOTE: Qualified Version Definitions:

- Military - QML certified for Military and Defense Applications


NOTES: A. All linear dimensions are in millimeters.
B. This drawing is subject to change without notice.


NOTES: A. All linear dimensions are in millimeters.
B. This drawing is subject to change without notice.
C. Falls within JEDEC MS-026

## IMPORTANT NOTICE

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, modifications, enhancements, improvements, and other changes to its products and services at any time and to discontinue any product or service without notice. Customers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All products are sold subject to Tl's terms and conditions of sale supplied at the time of order acknowledgment.
TI warrants performance of its hardware products to the specifications applicable at the time of sale in accordance with Tl's standard warranty. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by government requirements, testing of all parameters of each product is not necessarily performed.
TI assumes no liability for applications assistance or customer product design. Customers are responsible for their products and applications using TI components. To minimize the risks associated with customer products and applications, customers should provide adequate design and operating safeguards.
TI does not warrant or represent that any license, either express or implied, is granted under any TI patent right, copyright, mask work right, or other TI intellectual property right relating to any combination, machine, or process in which TI products or services are used. Information published by TI regarding third-party products or services does not constitute a license from TI to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from Tl under the patents or other intellectual property of TI .
Reproduction of Tl information in Tl data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. Reproduction of this information with alteration is an unfair and deceptive business practice. TI is not responsible or liable for such altered documentation. Information of third parties may be subject to additional restrictions.

Resale of TI products or services with statements different from or beyond the parameters stated by TI for that product or service voids all express and any implied warranties for the associated Tl product or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

TI products are not authorized for use in safety-critical applications (such as life support) where a failure of the TI product would reasonably be expected to cause severe personal injury or death, unless officers of the parties have executed an agreement specifically governing such use. Buyers represent that they have all necessary expertise in the safety and regulatory ramifications of their applications, and acknowledge and agree that they are solely responsible for all legal, regulatory and safety-related requirements concerning their products and any use of TI products in such safety-critical applications, notwithstanding any applications-related information or support that may be provided by TI. Further, Buyers must fully indemnify Tl and its representatives against any damages arising out of the use of Tl products in such safety-critical applications.
TI products are neither designed nor intended for use in military/aerospace applications or environments unless the TI products are specifically designated by TI as military-grade or "enhanced plastic." Only products designated by TI as military-grade meet military specifications. Buyers acknowledge and agree that any such use of TI products which TI has not designated as military-grade is solely at the Buyer's risk, and that they are solely responsible for compliance with all legal and regulatory requirements in connection with such use.
TI products are neither designed nor intended for use in automotive applications or environments unless the specific Tl products are designated by TI as compliant with ISO/TS 16949 requirements. Buyers acknowledge and agree that, if they use any non-designated products in automotive applications, TI will not be responsible for any failure to meet such requirements.
Following are URLs where you can obtain information on other Texas Instruments products and application solutions:

| Products |  |
| :--- | :--- |
| Amplifiers |  |
| Data Converters | amplifier.ti.com |
| DSP | dataconverter.ti.com |
| Clocks and Timers | dsp.ti.com |
| Interface | www.ti.com/cocks |
| Logic | nterace.ti.com |
| Power Mgmt | ogic.ti.com |
| Microcontrollers | Dowe.ti.com |
| RFID | nicrocontroler.ti.com |
| RF/IF and ZigBee® Solutions | NWw.ti-rfid.com |
|  |  |


| Applications |  |
| :---: | :---: |
| Audio | www.ti.com/audio |
| Automotive | www.ticom/automotive |
| Broadband | www.ti.com/broadband |
| Digital Control | www.ti.com/digitalcontrol |
| Medical | www.ti.com/medica |
| Military | www.ti.com/military |
| Optical Networking | www.ticom/opticalnetwork |
| Security | www.ti.com/security |
| Telephony | www.ti.com/telephony |
| Video \& Imaging | www.ticom/vided |
| Wireless | www.ti.com/wireless |

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265
Copyright © 2008, Texas Instruments Incorporated

